## HIGH Q/LOW ESR MULTILAYER CERAMIC CHIP CAPACITORS - GHQ SERIES -

## SCOPE

- Used at high frequencies, small temperature coefficient of capacitance, typical within +/-30ppm/C required for NPO (COG) classification.

- Excellent conductivity internal electrode

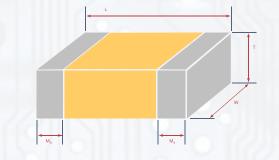
### FEATURES

High Q and low ESR performance at high frequency.
Quality improvement of telephone calls for low power loss and better performance

### APPLICATIONS

- Mobile telecommunication; mobile phones, WLAN
- RF module: power amplifier, VCO
- Tuners

### CONSTRUCTION AND DIMENSIONS

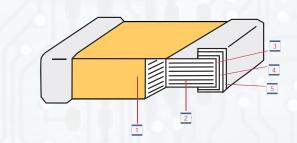


NO.	NA	AME	NP0		
1	Ceramio	c Material	CaZrO <sub>3</sub>		
2	Inner e	lectrode	Ni		
3	1	Inner layer	Cu		
4	Termination	Middle layer	Ni		
5		Outer layer	Sn		



SIZE INCH (MM)	L (MM)	W (MM)	T (MM)	REMARK	Мв (MM)
0201 (0603)	0.6±0.03	0.3±0.03	0.3±0.03	#	0.15±0.05
0402 (1005)	1.00±0.05	0.50±0.05	0.50±0.05	#	0.25+0.05/-0.10
0/00/01/000	1.60±0.10	0.80±0.10	0.80±0.07		0.40±0.15
0603 (1608)	1.60±0.15/-0.10	0.80±0.15/-0.10	0.80±0.15/-0.10		0.40±0.15
0805 (2012)	2.00±0.15	1.25±0.10	0.80±0.10		
0003 (2012)	2.00±0.15	1.25±0.10	1.25±0.10	#	0.50±0.20

#Reflow soldering only is recommended



### ORDERING INFORMATION

GHQ	10	CG	101	J	100	N	Т
PRODUCT TYPE	SIZE	DIELECTRIC	CAPACITANCE	TOLERANCE	RATED VOLTAGE	TERMINATION	PACKAGING
	02 - 0201 (0603) 04 - 0402 (1005) 10 - 0603 (1608) 21 - 0805 (2012)	CG - NPO (COG)	Two significant digits followed by no of zeros. Use R in place of decimal point.	A: $\pm$ 0.05pF B: $\pm$ 0.1pF C: $\pm$ 0.25pF D: $\pm$ 0.5pF F: $\pm$ 1% G: $\pm$ 2% J: $\pm$ 5%	25 - 25 VDC 50 - 50 VDC 100 - 100 VDC 200 - 200 VDC 250 - 250 VDC 500 - 500 VDC 630 - 630 VDC	N: Cu/Ni/Sn	T: 7" reel TD: 13"reel

### CAPACITANCE RANGE

	SION (MM)	0	GHQ0	2	0	GHQ04			GH	Q10		/		GH	Q21		
	.(L1)		0.6+/-0.03	3		.00±0.0	5	1.60	±10	1.60+0.	15/-0.10			2.00	±0.15		
	W		).3+/-0.0			).50±0.0		-	±0.10		15/-0.10				25±0.10		
BW	(L2/L3)		0.15+/-0.0	5	0.2	5+0.05/-	0.10	111	0.40	±0.15				0.50	.50±0.20		
	lectric		NPO	0	012	COG	0.1.0	1		CG		-			DG		
			1	-			-	-							50		
	(max)		0.33			0.55		0.	87	0.	95		0.9			1.35	
Rated	Voltage	10	16	25	16	25	50	16	25	50	100	50	100	200	250	500	630
Cap	. Range																
0.3pF	OR3																
0.4pF	OR4					1											
0.5	OR5																
0.6	OR6																
0.7	0R7																
0.8	OR8																
0.9	0R9																
1	1R0																
1.2	1R2																
1.5	1R5																
1.8	1R8																
2.2	2R2																
2.7	2R7																
3.3	3R3																
3.9	3R9																
4.7	4R7																
5.6	5R6																
6.8	6R8																
8.2	8R2																
10pF	100																
12	120	_															
15	150																
18 22	180 220	_															
22	220																
33	330																
39	390																
47	470				-												
56	560				-												
68	680																
82	820																
100	101																
120	121																
150	151																
180	181																
220	221																
270	271																
330	331																
390	391																
470	471														1000		
560	561																
680	681												1.1.1				
820	821																
1000	102																
1200	122																
1500	152																
1800	182	-															
2200	222																
2700	272					100	11										
3300	332					and the second second											

1. 0402, Capacitance <0.5pF, on request

2. For more information about products with special capacitance or other data, please contact your Cal-Chip Sales Representative

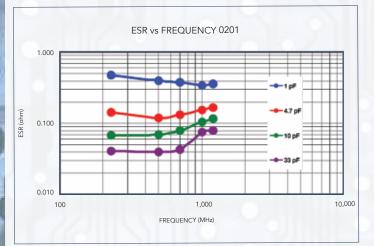


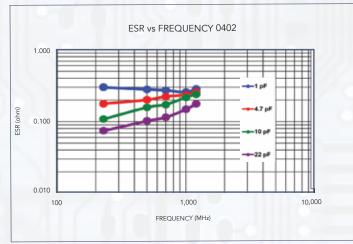
#### GENERAL ELECTRICAL DATA

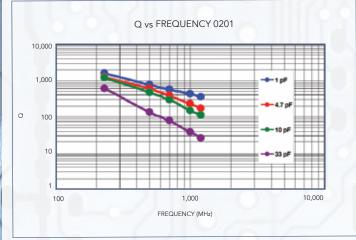
DIALECTRIC	NPO
SIZE	0201, 0402, 0603, 0805
CAPACITANCE RANGE	0201: 0.1pF to 3300pF 0402: 0.5pF to 470pF** 0603: 0.5pF to 3300pF 0805: 0.5pF to 390pF
CAPACITANCE TOLERANCE**	Cap≤5pF: A(±0.05PF), B (±0.1pF), C (±0.25pF) 5pF <cap<10pf: (±0.25pf),="" (±0.5pf)<br="" c="" d="">Cap≥10pF: F (±1%), G (±2%), J (±5%)</cap<10pf:>
RATED VOLTAGE (WVDC)	16V, 25V, 50V, 100V, 200V, 250V, 500V, 630V
Q*	Cap<30pF: Q≥400+20C Cap:≥30pF: Q≥1000
INSULATION RESISTANCE AT UR	$\geq$ 10G $\Omega$ or RxC $\geq$ 100 $\Omega$ - F whichever is smaller
OPERATING TEMPERATURE	-55° to +125°C
CAPACITANCE CHARACTERISTIC	±30ppm/°C
TERMINATION	Ni/Si (lead-free termination)

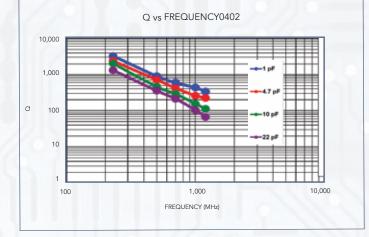
#1: NP0, 0.1pF product only provide B tolerance \*Measured at the condition of 25°C ambient temperature 30–70% related humidity. Apply 1.0.8:02/vms, 1.0MHzz±10% for Cap≤1000pF and 1.0±0.2Vrms, 1.0kHz±10% for Cap>1000pF. \*\*0402, Capacitance <0.5pF: On request.

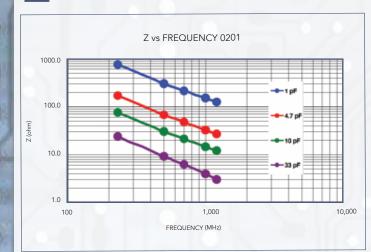
### ELECTRICAL CHARACTERISTICS

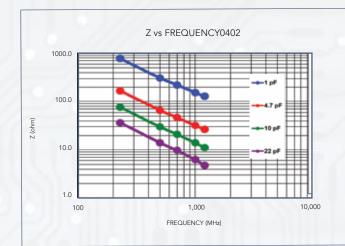


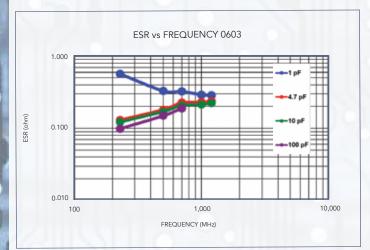


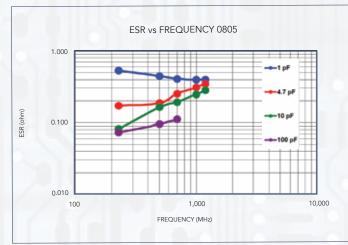


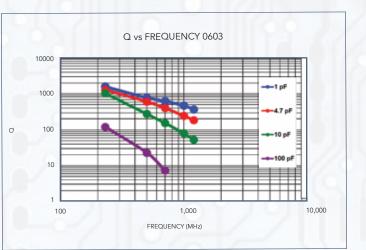


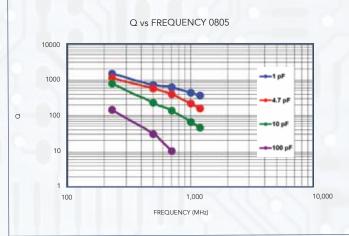






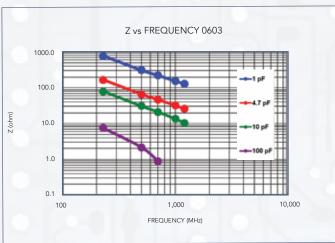


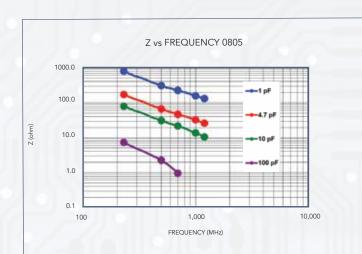


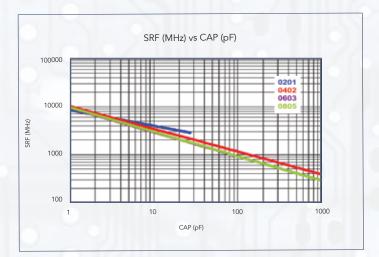














### RELIABILITY TEST CONDITIONS AND REQUIREMENTS

NO.	ITEM	TEST CONDITION	REQUIREMENTS			
1.	Visual and Mechanical		- No remarkable defect. - Dimensions to conform to individual specification sheet.			
2.	Capacitance	Cap≤1000pF, 1.0±0.2Vrms   1MHz±10%	- Shall not exceed the limits given in the detailed spec.			
3.	Q/D.F. (Dissapation Factor)	Cap>1000pF, 1.0±0.2Vrms I 1KHz±10% At 25°C ambient temperature.	NP0: Cap≥30pF, Q≥1000; Cap<30pF, Q≥400+20C			
ľ		- To apply (≤100V) 250% of rated voltage. - Duration 1 to 5 seconds - Charge and discharge current less than 50mA.				
4.	Dielectric Strength	- To apply (≤100V) 250% 200V - 300V ≥2 times VDC 500V - 999V ≥1.5 times VDC - Cut-off, set at 10mA - TEST = 15 sec. - RAMP = 0	- No evidence of damage or flas over during test.			
	Insulation	- Rated Voltage: <200V - To Apply rated voltage for max. 120 sec.	≥10GΩ			
5.	Resistance	- Rated Voltage: 200~630V - To Apply rated voltage (500V max.) for 60 sec.	≥10GΩ or RxC≥100Ω-F whichever is smaller			
6.	Temperature Coefficient	- With no electrical load. - Operating temperature: -55°~125°C at 25°C	- Capacitance change: within ±30ppm/°C			
7.	Adhesive Strength of Termination	<ul> <li>Pressurizing force: 5N (≤0603) and 10N (&gt;0603)</li> <li>Test time: 10±1 sec.</li> </ul>	- No remarkable damage or removal of the terminations.			
8.	Vibration Resistance	<ul> <li>Vibration frequency: 10-55 Hz/min.</li> <li>Total amplitude: 1.5mm</li> <li>Test time: 6hrs. (Two hrs each in three mutually perpendicular directions.)</li> <li>Measurement to be made after keeping at room temp. for 24±2 hrs.</li> </ul>	- No remarkable damage - Cap change and Q/D.F.: To meet initial spec.			
9.	Solderability	- Solder temperature: 235±5°C - Dipping time 2±0.5 sec.	- 95% min. coverage of all metalized area.			
10.	Bending Test	<ul> <li>The middle part of substrate shall be pressurized by means of the pressurizing rod at a rate of about 1 mm per second until the deflection becomes 1 mm and then the pressure shall be maintained for 5±1 sec.</li> <li>Measurement to be made after keeping at room temp. for 24±2 hrs</li> </ul>	<ul> <li>No remarkable damage</li> <li>Cap change: within ±5% or 0.5pF whichever is larger</li> <li>(This capacitance change the means change of capacitance under specified flexure of substrate from the capacitance measured before the test.)</li> </ul>			
11.	Resistance to Soldering Heat	<ul> <li>Solder temperature: 260±5°C</li> <li>Dipping time: 10±1sec</li> <li>Preheating: 120 to 150°C for 1 minute before immerse the capacitor in a eutectic solder</li> <li>Before initial measurement (Class II only): Perform 150+0/-10°C for 1 hr and then set for 24±2 hrs at room temp.</li> <li>Measurement to be made after keeping at room temp. for 24±2 hrs.</li> </ul>	<ul> <li>No remarkable damage</li> <li>Cap change: within ±2.5% or ±0.25pF whichever is larger</li> <li>Q/D.F., I.R. and dielectric strength: To meet initial requirements.</li> <li>25% max. leaching on each edge.</li> </ul>			
12.	Temperature Cycle	- Conduct the five cycles according to the temperatures and time.         STEP       TEMP. (°C)         1       Min. operating temp. +0/-3         2       Room Temp         3       Min. operating temp. +0/-3         4       Room Temp         2~3         - Before initial measurement (Class II only): perform 150+0/-10°C for 1         hr and then set for 24±2 hrs at room temp.         - Measurement to be made after keeping at room temp. for 24±2 hrs	- No remarkable damage - Cap change: within ±2.5% or ±0.25pF whichever is larger - Ω/D.F., I.R. and dielectric strength: To meet initial requirements.			
13.	Humidity (Damp Heat) Steady State	<ul> <li>Test temp.: 40±2°C</li> <li>Humidity 90~95% RH</li> <li>Test time: 500+24/-0 hrs</li> <li>Before initial measurement (Class II only): Perform 150+0/-10C for</li> <li>1 hr and then set for 24±2 hrs at room temp.</li> <li>Measurement to be made after keeping at room temp. for 24±2 hrs.</li> </ul>	- No remarkable damage - Cap change: within ±5% or ±0.5pF whichever is larger - Q/D.F. value NP0: Cap≥30pF, Q≥350, 10pF≤Cap≤30pF, Q≥275+2.5C Cap<10pF, Q≥200+10C -I.R.: ≥1GΩ or RxC≥50Ω -F whichever is smaller			



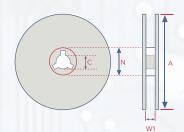


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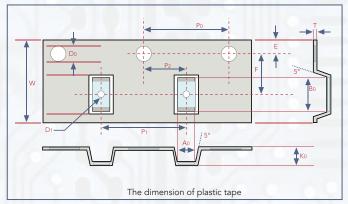
NO.	ITEM	TEST CONDITION	REQUIREMENTS				
0 14.	Humidity (Damp Heat) Load	<ul> <li>Test temp.: 40±2°C</li> <li>Humidity 90~95% RH</li> <li>Test time: 500+24/-0 hs</li> <li>To apply voltage: rated voltage (Max. 500V)</li> <li>Before initial measurement (Class II only): To apply test voltage for 1hr at 40°C and then set for 24±2 hrs at room temp.</li> <li>Measurement to be made after keeping at room temp. for 24±2 hrs.</li> </ul>	- No remarkable damage - Cap change: within $\pm 7.5\%$ or $\pm 0.75$ pF whichever is larger - $\Omega/D.F$ , value: NPO: Cap $\geq 30$ pF, $\Omega \geq 350$ ; $10$ pF $\leq$ Cap $< 30$ pF, $\Omega \geq 100+10/3$ C -I.R: $\geq 1G\Omega$ or RxC $\geq 25\Omega$ - F whichever is smaller				
15	Humidity Temperature Load (Endurance)	- Test temp.: NP0: 125±3°C     - To Apply Voltage:         (1) <500V: 200% of rated voltage.         (2) 500V: 150% of rated voltage.         (3) ≥ 630V: 120% of rated voltage.         - Test time: 1000+24/-0 hrs         - To apply voltage : rated voltage.         - Before initial measurement (Class II only): To apply test voltage for 1 hr at test temp. and then set for 24±2 hrs at room temp.         - Measurement to be made after keeping at room temp. for 24±2 hrs.	- No remarkable damage - Cap change: within ±3.0% or ±0.3pF whichever is larger - Q/D.F. value: NP0: Cap30pF Q≥350 10pF≤Cap<30pF, Q≥275+2.5C Cap<10pF, q≥200+10C -I.R.: ≥1GΩ or RxC≥50Ω-F whichever is smaller.				

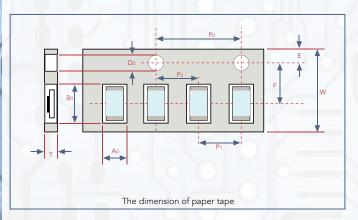
### PACKAGING



SIZE		0201, 0402, 0603, 0805		
REEL SIZE	7"	10″	13″	
С	13.0+0.5/-0.2	13.0+0.5/-0.2	13.0+0.5/-0.2	
W1	8.4+1.5/-0	8.4+1.5/-0	8.4+1.5/-0	
А	178.0±0.10	250.0±1.0	330.0±1.0	
N	60.0+1.0/-0	100+1.0	100+1.0	

SIZE	THICKNESS (mm)	PAPER	R TAPE	PLASTI	C TAPE
JIZE	/SYMBOL	7" REEL	13" REEL	7" REEL	13" REEL
0201	0.30±0.3	15k	70k		
0402	0.50±0.5	10k	50k		
0603	0.80±0.07	4k	15k	177	
0003	0.80±0.15/-0.10	4k	15k		
0805	0.80±0.10	4k	15k		
0805	1.25±0.10			3k	10k





# Cal-Chip

### STORAGE AND HANDLING CONDITIONS

(1) To store products at 5 to 40°C ambient temperature and 20 to 70%. related humidity conditions.
(2) The product is recommended to be used within one year after shipment. Check solderability in case of shelf life extension is needed.

Cautions:

a. The corrosive gas reacts on the terminal electrodes of capacitors, and results in the poor solderability. Do not store the capacitors in the ambience of corrosive gas (e.g., hydrogen sulfide, sulfur dioxide, chlorine, ammonia gas etc.)

b. In corrosive atmosphere, solderability might be degraded, and silver migration might occur to cause low reliability.

c. Due to the dewing by rapid humidity change, or the photochemical change of the terminal electrode by direct sunlight, the solderability and electrical performance may deteriorate. Do not store capacitors under direct sunlight or dewing condition. To store products on the shelf and avoid exposure to moisture.

### RECOMMENDED SOLDERING CONDITIONS

The lead-free termination MLCCs are not only to be used on SMT against lead-free solder paste, but also suitable against lead-containing solder paste. If the optimized solder joint is requested, increasing soldering time, temperature and concentration of N<sub>2</sub> within oven are recommended.

